



1/25/2008

**RELIABILITY MONITOR REPORT  
FOR**

**MFN Dual Poly 0.8 $\mu$ m CMOS**

**MAXIM Integrated Products**

**120 San Gabriel Dr.  
Sunnyvale, CA 94086**

**This Report was prepared by  
Maxim Reliability Engineering**

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX2116UTL	MAX2116UTL+	MAX2606EUT+
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The calculated failure rate for devices using this process is:

**FAILURE RATE:**                      **MTTF (YRS): 54646**                      **FITS: 2.1**

The parameters used to calculate this failure rate are as follows:

**Cf: 60%**                      **Ea: 0.7**                      **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between and .

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**Process Information:**

Process Description:                      MFN Dual Poly 0.8µm CMOS

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**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
HIGH TEMP OP LIFE	0537	MAX2116UTL	135C, 5.25V	1000 HRS	76	0	
HIGH TEMP OP LIFE	0547	MAX2116UTL+	135C, 5.25V	1000 HRS	77	0	
HIGH TEMP OP LIFE	0619	MAX2606EUT+	135C, 5.25V	1000 HRS	79	0	
HIGH TEMP OP LIFE	0620	MAX2116UTL+	135C, 5.25V	1000 HRS	50	0	
				<b>Total:</b>		<b>0</b>	

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